

<b>Notice of References Cited</b>	Application/Control No. 10/708,822	Applicant(s)/Patent Under Reexamination BEENAU ET AL.	
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#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2003/0223625	12-2003	Hillhouse et al.	382/125
	B	US-2002/0191816	12-2002	Maritzen et al.	382/115
	C	US-2002/0087869	07-2002	Kim, Jinsam	713/186
	D	US-2001/0036301	11-2001	Yamaguchi et al.	382/125
	E	US-6,233,348	05-2001	Fujii et al.	382/125
	F	US-RE36,580	02-2000	Bogosian, Jr., Charles A.	382/116
	G	US-2005/0005172	01-2005	Haala, Catherine A.	713/202
	H	US-2005/0001711	01-2005	Doughty et al.	340/005.74
	I	US-2003/0037264	02-2003	Ezaki et al.	713/202
	J	US-2005/0103839	05-2005	Hewel, Karl-Harald	235/380
	K	US-2004/0118930	06-2004	Berardi et al.	235/492
	L	US-5,438,184	08-1995	Roberts et al.	235/380
	M	US-6,636,620	10-2003	Hoshino, Satoshi	382/124

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Smart Card Technology and Applications. <a href="http://disc.cba.uh.edu/~rhirsch/fall96/lara.htm">http://disc.cba.uh.edu/~rhirsch/fall96/lara.htm</a>
	V	
	W	
	X	

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#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2005/0122209	06-2005	Black, Gerald R.	340/005.52
	B	US-2004/0006497	01-2004	Nestor et al.	705/5
	C	US-2002/0179704	12-2002	Deaton, Tom R.	235/383
	D	US-2002/0186133	12-2002	Loof, Per Olof	340/572.1
	E	US-2005/0149926	07-2005	Saltz, Michael K.	718/001
	F	US-2004/0155101	08-2004	Royer et al.	235/379
	G	US-2004/0083380	04-2004	Janke, Marcus	713/194
	H	US-2003/0236704	12-2003	Antonucci, Donna A.	705/14
	I	US-2003/0009382	01-2003	D'Arbeloff et al.	705/17
	J	US-2003/0125054	07-2003	Garcia, Sergio Salvador	455/466
	K	US-2002/0072349	06-2002	Geiselman et al.	455/411
	L	US-2002/0043566	04-2002	Goodman et al.	235/492
	M	US-6,588,673	07-2003	Chan et al.	235/492

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
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	X	

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,257,486	07-2001	Teicher et al.	235/380
	B	US-5,180,902	01-1993	Schick et al.	235/380
	C	US-2005/0097038	05-2005	Yu et al.	705/040
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	P					
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	S					
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*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	W	
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